

Title (en)
PROCESS FOR OPERATING A TIME-OF-FLIGHT SECONDARY ION MASS SPECTROMETER

Title (de)
VERFAHREN ZUM BETREIBEN EINES FLUGZEIT-SEKUNDÄRIONEN-MASSENSPEKTROMETERS

Title (fr)
PROCEDE D'EXPLOITATION D'UN SPECTROMETRE DE MASSE POUR IONS SECONDAIRES FONCTIONNANT PAR MESURE DU TEMPS DE VOL

Publication
EP 0708976 A1 19960501 (DE)

Application
EP 95920015 A 19950510

Priority

- DE 4416413 A 19940510
- EP 9501767 W 19950510

Abstract (en)
[origin: DE4416413A1] The invention pertains to a process for operating a time-of-flight secondary ion mass spectrometer for analysis of mass spectra, wherein a number of finely structured mass ranges appear in isolation at major intervals, involving the following steps: a) a surface of a material sample is bombarded with primary ion pulses that follow each other at regular time intervals t_z (cycle time), b) the secondary ions of various masses m released from the material sample surface by the primary ions are accelerated to the same energy, c) the mas-dependent time of flight t is measured over a path l and the mass is determined therefrom. To increase the resolution and the signal-to-noise ratio the process is characterized in that: d) each primary ion pulse consists of a number of subpulses, e) each subpulse is so narrow that it allows for resolution of the finely structured mass ranges, f) the interval t_B between the subpulses is greater than the width of the finely structured mass ranges, g) the number n of subpulses is selected so that $n \cdot t_B$ is smaller than the intervals between the finely structured mass ranges, h) the n subpulse spectra of each finely structured mass range are added up.

IPC 1-7
H01J 49/40; **H01J 37/252**; **G01N 23/225**

IPC 8 full level
G01N 23/225 (2006.01); **G01Q 60/44** (2010.01); **H01J 37/252** (2006.01); **H01J 49/40** (2006.01)

CPC (source: EP US)
H01J 49/40 (2013.01 - EP US)

Citation (search report)
See references of WO 9531000A1

Designated contracting state (EPC)
FR GB SE

DOCDB simple family (publication)
DE 4416413 A1 19951123; **DE 4416413 C2 19960328**; EP 0708976 A1 19960501; EP 0708976 B1 19971112; JP 3358065 B2 20021216; JP H09500486 A 19970114; US 5633495 A 19970527; WO 9531000 A1 19951116

DOCDB simple family (application)
DE 4416413 A 19940510; EP 9501767 W 19950510; EP 95920015 A 19950510; JP 52869795 A 19950510; US 57864696 A 19960209